SCCS032B - SEPTEMBER 1994 - REVISED OCTOBER 2001

- Function, Pinout, and Drive Compatible With FCT and F Logic
- Reduced V_{OH} (Typically = 3.3 V) Version of Equivalent FCT Functions
- Edge-Rate Control Circuitry for Significantly Improved Noise Characteristics
- I_{off} Supports Partial-Power-Down Mode Operation
- Matched Rise and Fall Times
- Fully Compatible With TTL Input and Output Logic Levels
- 64-mA Output Sink Current
 32-mA Output Source Current
- Independent Register for A and B Buses
- Multiplexed Real-Time and Stored Data Transfer
- 3-State Outputs

(TOP VIEW) CPAB [24 VCC SAB [] 2 23 CPBA GAB [] 3 22 T SBA 21 GBA $A_1 \prod 4$ 20 B₁ A₂ [] 5 19 B₂ A₃ 🛮 6 Α₄Γ 18∏ B₃ A₅ 🛮 8 17 B₄ A₆ 🛮 9 16 B₅ 15 B₆ A₇ 🛮 10 14 🛮 B₇ A₈ 📙 11 GND **1**12 13 B₈

Q OR SO PACKAGE

description

The CY74FCT652T consists of bus transceiver circuits, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the input bus or from the internal storage registers. GAB and GBA inputs control the transceiver functions. Select-control (SAB and SBA) inputs select either real-time or stored-data transfer. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. A low input level selects real-time data, and a high input level selects stored data.

Data on the A or B data bus, or both, can be stored in the internal D-type flip-flops by low-to-high transitions of the appropriate clock (CPAB or CPBA) inputs, regardless of the select or enable levels of the control pins. When SAB and SBA are in the real-time transfer mode, it also is possible to store data without using the internal D-type flip-flops by simultaneously enabling GAB and $\overline{\text{GBA}}$. In this configuration, each output reinforces its input. Thus, when all other data sources to the two sets of bus lines are at high impedance, each set of bus lines remains at its last state.

This device is fully specified for partial-power-down applications using I_{off} . The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



ORDERING INFORMATION

TA	PACI	(AGE [†]	SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING	
	QSOP - Q	Tape and reel	5.4	CY74FCT652CTQCT	FCT652C	
	SOIC - SO	Tube	5.4	CY74FCT652CTSOC	FCT652C	
	3010 - 30	Tape and reel	5.4	CY74FCT652CTSOCT	FC1652C	
–40°C to 85°C	QSOP - Q	Tape and reel	6.3	CY74FCT652ATQCT	FCT652A	
	SOIC - SO	Tube	6.3	CY74FCT652ATSOC	FCT652A	
	3010 - 30	Tape and reel	reel 6.3 CY74FCT652ATSOCT		FC1052A	
	QSOP - Q	Tape and reel	9	CY74FCT652TQCT	FCT652	

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE

_								
		INP	UTS			DAT	A I/O	OPERATION OR
GAB	GBA	CPAB	СРВА	SAB	SBA	A ₁ -A ₈	B ₁ -B ₈	FUNCTION
L	Н	H or L	H or L	Χ	Х	Input	Input	Isolation
L	Н	1	\uparrow	X	X	Input	Input	Store A and B data
Х	Н	1	H or L	Х	Х	Input	Unspecified§	Store A, hold B
Н	Н	\uparrow	\uparrow	χ‡	X	Input	Output	Store A in both registers
L	Х	H or L	↑	Χ	Х	Unspecified§	Input	Hold A, store B
L	L	1	\uparrow	Χ	χ‡	Output	Input	Store B in both registers
L	L	Х	Х	Χ	L	Output	Input	Real-time B data to A bus
L	L	Χ	H or L	Χ	Н	Output	Input	Stored B data to A bus
Н	Н	Х	Х	L	Х	Input	Output	Real-time A data to B bus
Н	Н	H or L	X	Н	Χ	Input	Output	Stored A data to B bus
Н	L	H or L	H or L	Н	Н	Output	Output	Stored A data to B bus and Stored B data to A bus

H = High logic level, L = Low logic level, X = Don't care, ↑ = Low-to-high transition



[‡] Select control = L: clocks can occur simultaneously. Select control = H: clocks must be staggered in order to load both registers.

[§] The data output functions can be enabled or disabled by various signals at the GAB and GBA inputs. Data input functions always are enabled, i.e., data at the bus pins are stored on every low-to-high transition of the clock inputs.

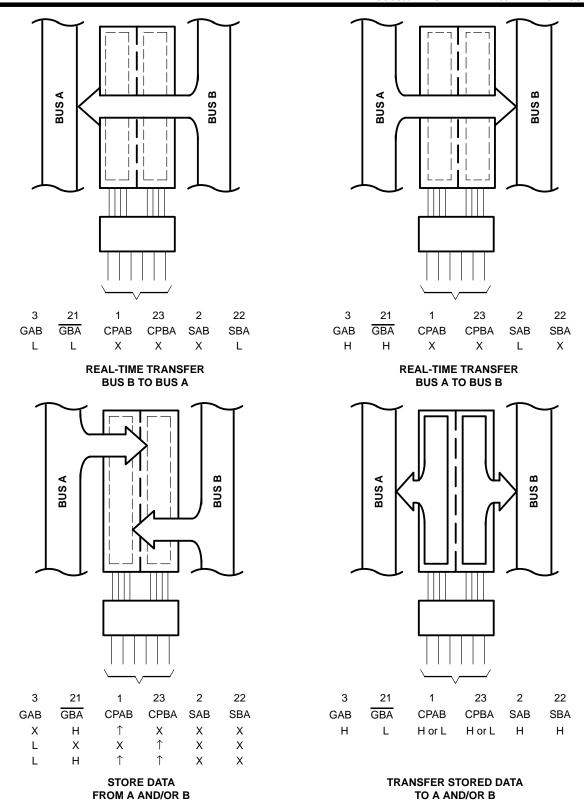
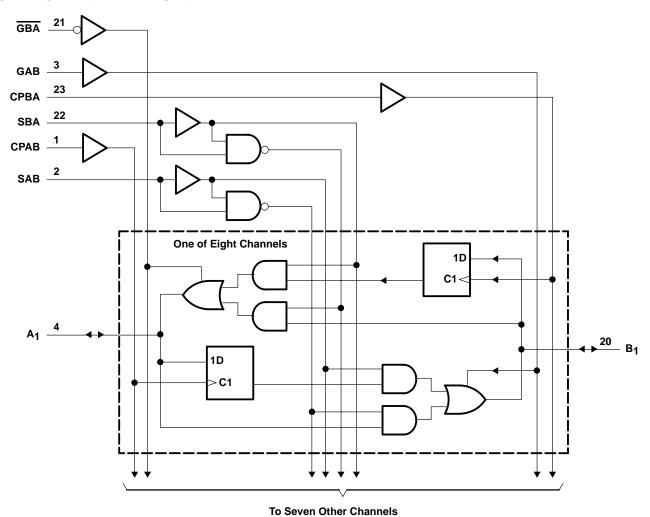


Figure 1. Bus-Management Functions



logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range to ground potential		0.5	\mbox{V} to 7 \mbox{V}
DC input voltage range		0.5	\mbox{V} to 7 \mbox{V}
DC output voltage range		0.5	\mbox{V} to 7 \mbox{V}
DC output current (maximum sink current/pin)			120 mA
Package thermal impedance, θ _{JA} (see Note 1)): Q package		61°C/W
	SO package		46°C/W
Ambient temperature range with power applied	d, T _A	. −65°C t	io 135°C
Storage temperature range, T _{stq}		. −65°C t	io 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.75	5	5.25	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			8.0	V
ІОН	High-level output current			-32	mA
loL	Low-level output current			64	mA
TA	Operating free-air temperature	-40		85	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.



NOTES: 1. The package thermal impedance is calculated in accordance with JESD 51-7.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	S	MIN	TYP [†]	MAX	UNIT
V _{IK}	$V_{CC} = 4.75 \text{ V},$	I _{IN} = -18 mA			-0.7	-1.2	V
V	V 4.75.V	I _{OH} = -32 mA		2			V
VOH	V _{CC} = 4.75 V	I _{OH} = -15 mA		2.4	3.3		V
V _{OL}	V _{CC} = 4.75 V,	I _{OL} = 64 mA			0.3	0.55	V
V _{hys}	All inputs				0.2		V
Ц	V _{CC} = 5.25 V,	V _{IN} = V _{CC}				5	μΑ
lн	V _{CC} = 5.25 V,			±1	μΑ		
Ι _{ΙL}	V _{CC} = 5.25 V,	V _{IN} = 0.5 V				±1	μΑ
lozh	V _{CC} = 5.25 V,	V _{OUT} = 2.7 V				10	μΑ
l _{OZL}	V _{CC} = 5.25 V,	V _{OUT} = 0.5 V				-10	μΑ
l _{OS} ‡	V _{CC} = 5.25 V,	V _{OUT} = 0 V		-60	-120	-225	mA
I _{off}	V _{CC} = 0 V,	V _{OUT} = 4.5 V				±1	μΑ
Icc	$V_{CC} = 5.25 \text{ V},$	$V_{IN} \le 0.2 V$,	$V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.1	0.2	mA
ΔlCC	$V_{CC} = 5.25 \text{ V}, V_{IN} = 3$.4 V , $f_1 = 0$, Outputs op	en		0.5	2	mA
I _{CCD} ¶		out switching at 50% duty / _{IN} ≤ 0.2 V or V _{IN} ≥ V _{CC}			0.06	0.12	mA/ MHz
	$V_{CC} = 5.25 \text{ V},$ $f_0 = 10 \text{ MHz},$	One bit switching at f ₁ = 5 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.7	1.4	
. #	Outputs open,	at 50% duty cycle	V _{IN} = 3.4 V or GND		1.2	3.4	A
IC#	GAB = GBA = GND, SAB = CPAB = GND,	Eight bits switching at f ₁ = 5 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		2.8	5.6	mA
	SBA = V _{CC}	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		5.1	14.6	
Ci				5	10	pF	
Co					9	12	pF

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

IC = Total supply current

ICC = Power-supply current with CMOS input levels

 ΔI_{CC} = Power-supply current for a TTL high input ($V_{IN} = 3.4 \text{ V}$)

 D_H = Duty cycle for TTL inputs high N_T = Number of TTL inputs at D_H

 I_{CCD} = Dynamic current caused by an input transition pair (HLH or LHL)

f₀ = Clock frequency for registered devices, otherwise zero

f₁ = Input signal frequency

N₁ = Number of inputs changing at f₁

All currents are in milliamperes and all frequencies are in megahertz.

Values for these conditions are examples of the ICC formula.



Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, IOS tests should be performed last.

 $[\]$ Per TTL-driven input ($V_{IN} = 3.4 \text{ V}$); all other inputs at V_{CC} or GND

 $[\]P$ This parameter is derived for use in total power-supply calculations.

[#] I_C = I_{CC} + Δ I_{CC} × D_H × N_T + I_{CCD} (f₀/2 + f₁ × N₁) Where:

CY74FCT652T **8-BIT REGISTERED TRANSCEIVER** WITH 3-STATE OUTPUTS SCCS032B – SEPTEMBER 1994 – REVISED OCTOBER 2001

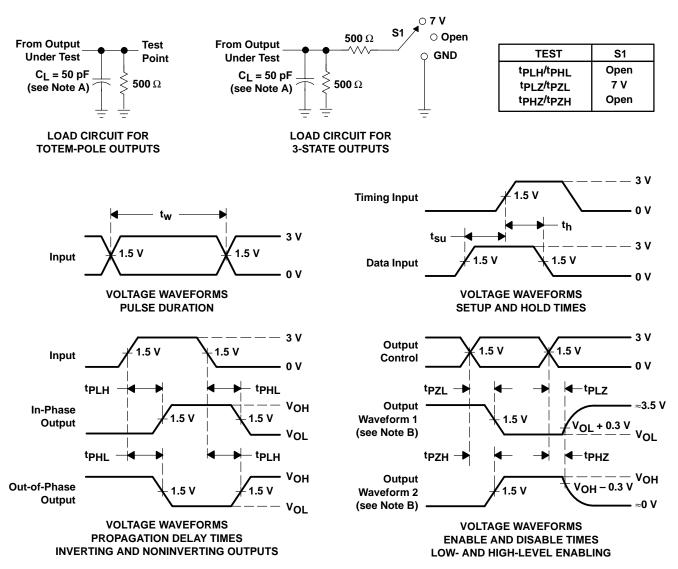
timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 2)

					CY74FCT	652AT	CY74FCT	UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
t _W	Pulse duration, clock high or low		6		5		5		ns
t _{su}	Setup time, before CPAB↑ or CPBA↑	A or B	4		2		2		ns
th	Hold time, after CPAB↑ or CPBA↑	A or B	2		1.5		1.5		ns

switching characteristics over operating free-air temperature range (see Figure 2)

PARAMETER	FROM	то	CY74FC	T652T	CY74FC	Г652AT	CY74FC1	652CT	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	
^t PLH	A or B	B or A	1.5	9	1.5	6.3	1.5	5.4	no
^t PHL	AOIB	BULA	1.5	9	1.5	6.3	1.5	5.4	ns
^t PZH	GAB or GBA	A or B	1.5	14	1.5	9.8	1.5	7.8	ns
t _{PZL}	GAD OF GBA	AOIB	1.5	14	1.5	9.8	1.5	7.8	113
^t PHZ	GAB or GBA	A or B	1.5	9	1.5	6.3	1.5	6.3	ns
t _{PLZ}	GAB OF GBA	AUIB	1.5	9	1.5	6.3	1.5	6.3	115
^t PLH	CPAB or CPBA	A or B	1.5	9	1.5	6.3	1.5	5.7	200
^t PHL	CPAB OI CPBA	AUID	1.5	9	1.5	6.3	1.5	5.7	ns
^t PLH	SBA or SAB	A or B	1.5	11	1.5	7.7	1.5	6.2	200
^t PHL	SDA UI SAB	AUIB	1.5	11	1.5	7.7	1.5	6.2	ns

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 2. Load Circuit and Voltage Waveforms







10-Jun-2014

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
CY74FCT652ATQCT	ACTIVE	SSOP	DBQ	24	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT652A	Samples
CY74FCT652ATQCTG4	ACTIVE	SSOP	DBQ	24	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT652A	Samples
CY74FCT652ATSOC	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT652A	Samples
CY74FCT652ATSOCT	ACTIVE	SOIC	DW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT652A	Samples
CY74FCT652ATSOCTE4	ACTIVE	SOIC	DW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT652A	Samples
CY74FCT652CTQCT	ACTIVE	SSOP	DBQ	24	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT652C	Samples
CY74FCT652CTSOC	OBSOLETI	SOIC	DW	24		TBD	Call TI	Call TI	-40 to 85	FCT652C	
CY74FCT652CTSOCE4	OBSOLETI	SOIC	DW	24		TBD	Call TI	Call TI	-40 to 85		
CY74FCT652CTSOCG4	OBSOLETI	SOIC	DW	24		TBD	Call TI	Call TI	-40 to 85		
CY74FCT652CTSOCT	ACTIVE	SOIC	DW	24	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT652C	Samples
CY74FCT652TQCT	ACTIVE	SSOP	DBQ	24	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT652	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.



PACKAGE OPTION ADDENDUM

10-Jun-2014

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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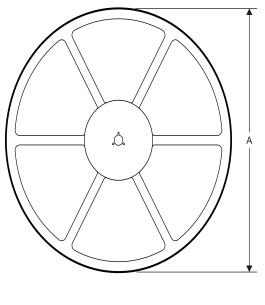
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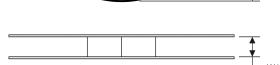
PACKAGE MATERIALS INFORMATION

16-Aug-2012 www.ti.com

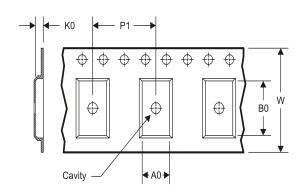
TAPE AND REEL INFORMATION

REEL DIMENSIONS





TAPE DIMENSIONS



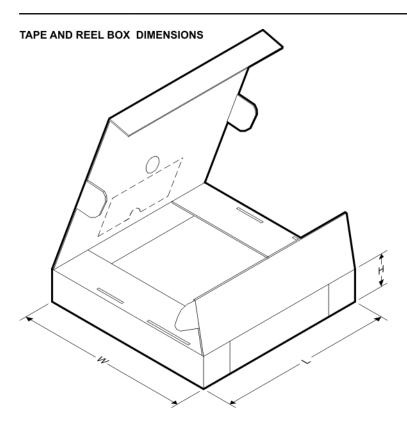
A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

TAPE AND REEL INFORMATION

*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CY74FCT652ATQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT652ATSOCT	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1
CY74FCT652CTQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT652CTSOCT	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1
CY74FCT652TQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1

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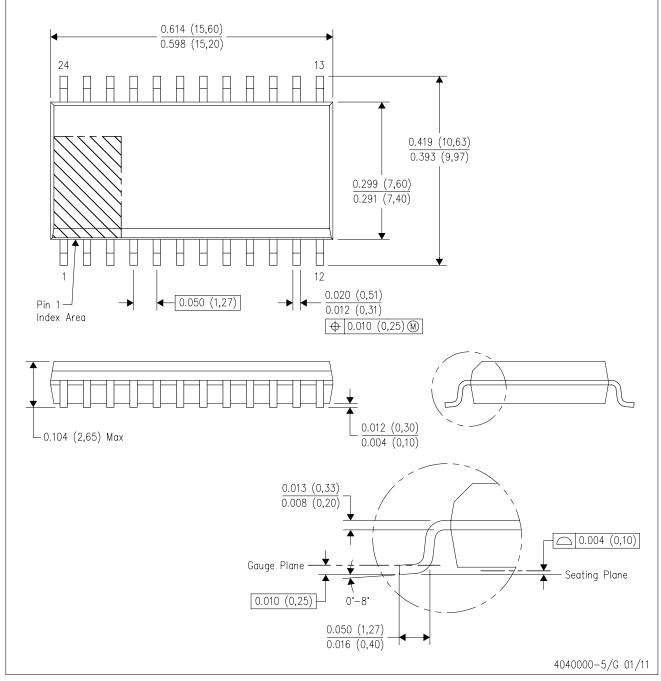


*All dimensions are nominal

7 til dilliciololio are nominal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CY74FCT652ATQCT	SSOP	DBQ	24	2500	367.0	367.0	38.0
CY74FCT652ATSOCT	SOIC	DW	24	2000	367.0	367.0	45.0
CY74FCT652CTQCT	SSOP	DBQ	24	2500	367.0	367.0	38.0
CY74FCT652CTSOCT	SOIC	DW	24	2000	367.0	367.0	45.0
CY74FCT652TQCT	SSOP	DBQ	24	2500	367.0	367.0	38.0

DW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



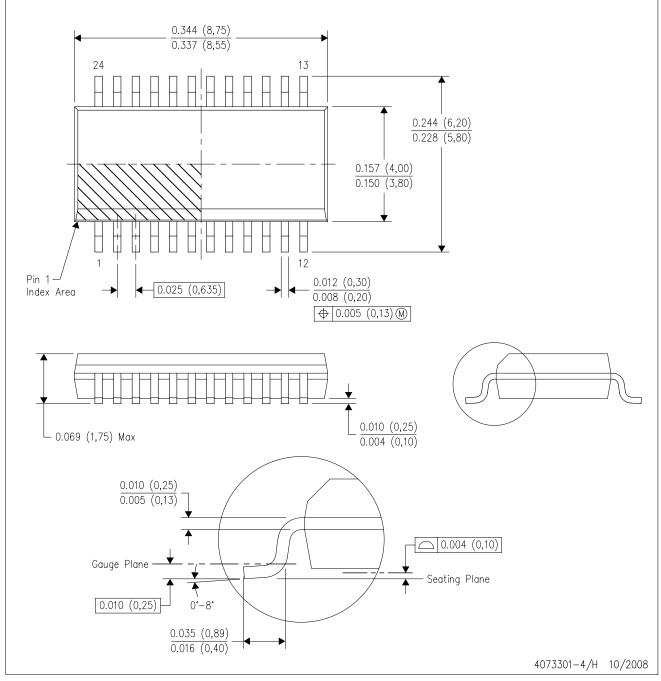
NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



DBQ (R-PDSO-G24)

PLASTIC SMALL-OUTLINE PACKAGE



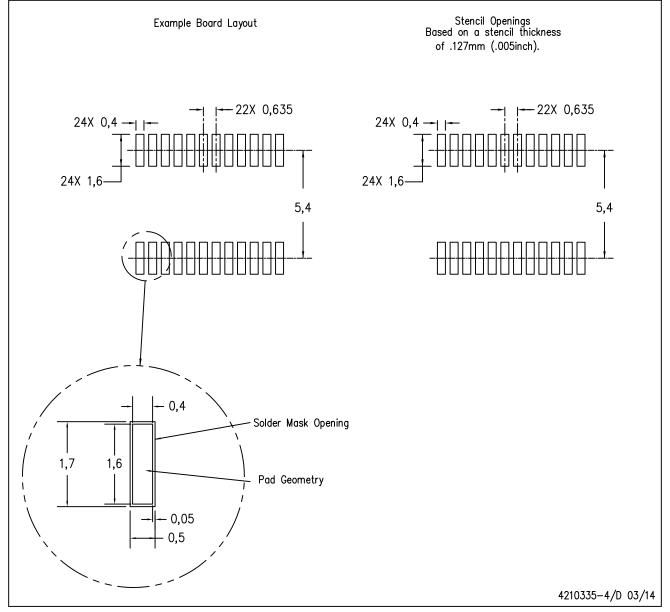
NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15) per side.
- D. Falls within JEDEC MO-137 variation AE.



DBQ (R-PDSO-G24)

PLASTIC SMALL OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



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Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have not been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

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